

Notice of References Cited	Application/Control No. 10/518,948		Applicant(s)/Patent Under Reexamination DOU ET AL.	
	Examiner Mark Kopec		Art Unit 1796	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,946,428	09-2005	Rey, Christopher Mark	505/237
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03/049208	06-2003	WO		
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Cimberle et al "Magnetic characterization of sintered MgB ₂ samples: effect of substitution or 'doping' with Li, Al and Si", Superconductor Science and Technology, 15(1) Jan 2002, pp 43-47.
	V	He et al "Reactivity of MgB ₂ with common substrate and electronic materials", Applied Physics Letters, 01/14/2002, Vol. 80 Issue 2, p291
	W	Jiang et al "Stoichiometry dependence of the critical current density in pure and nano-SiC doped MgB ₂ /Fe tapes", Physica C 451(Jan 2007) 71-76
	X	Dou et al "Superconductivity, critical current density, and flux pinning in MgB _{2-x} (SiC) _{x/2} superconductor after SiC nanoparticle doping", Condensed Matter Superconductivity, 4 July 2002, 1-7.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.